- **Low Clock-to-Cutoff-Frequency Ratio Error**
  TLC04/MF4A-50 . . . ±0.8%
  TLC14/MF4A-100 . . . ±1%
- **Filter Cutoff Frequency Dependent Only on External-Clock Frequency Stability**
- **Minimum Filter Response Deviation Due to External Component Variations Over Time and Temperature**
- **Cutoff Frequency Range From 0.1 Hz to 30 kHz, $V_{CC}± = ±2.5$ V**
- **5-V to 12-V Operation**
- **Self Clocking or TTL-Compatible and CMOS-Compatible Clock Inputs**
- **Low Supply-Voltage Sensitivity**
- **Designed to be Interchangeable With National MF4-50 and MF4-100**

D OR P PACKAGE
(TOP VIEW)

CLKIN	1	8	FILTER IN
CLKR	2	7	V_{CC+}
LS	3	6	AGND
V_{CC-}	4	5	FILTER OUT
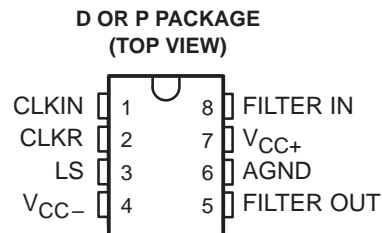
description

The TLC04/MF4A-50 and TLC14/MF4A-100 are monolithic Butterworth low-pass switched-capacitor filters. Each is designed as a low-cost, easy-to-use device providing accurate fourth-order low-pass filter functions in circuit design configurations.

Each filter features cutoff frequency stability that is dependent only on the external-clock frequency stability. The cutoff frequency is clock tunable and has a clock-to-cutoff frequency ratio of 50:1 with less than ±0. 8% error for the TLC04/MF4A-50 and a clock-to-cutoff frequency ratio of 100:1 with less than ±1% error for the TLC14/MF4A-100. The input clock features self-clocking or TTL- or CMOS-compatible options in conjunction with the level shift (LS) terminal.

The TLC04C/MF4A-50C and TLC14C/MF4A-100C are characterized for operation from 0°C to 70°C. The TLC04I/MF4A-50I and TLC14I/MF4A-100I are characterized for operation from −40°C to 85°C. The TLC04M/MF4A-50M and TLC14M/MF4A-100M are characterized over the full military temperature range of −55°C to 125°C.

AVAILABLE OPTIONS

T_A	CLOCK-TO-CUTOFF FREQUENCY RATIO	PACKAGE	
		SMALL OUTLINE (D)	PLASTIC DIP (P)
0°C to 70°C	50:1 100:1	TLC04CD/MF4A-50CD TLC14CD/MF4A-100CD	TLC04CP/MF4A-50CP TLC14CP/MF4A-100CP
−40°C to 85°C	50:1 100:1	TLC04ID/MF4A-50ID TLC14ID/MF4A-100ID	TLC04IP/MF4A-50IP TLC14IP/MF4A-100IP
−55°C to 125°C	50:1 100:1		TLC04MP/MF4A-50MP TLC14MP/MF4A-100MP

The D package is available taped and reeled. Add the suffix R to the device type (e.g., TLC04CDR/MF4A-50CDR).

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functional block diagram
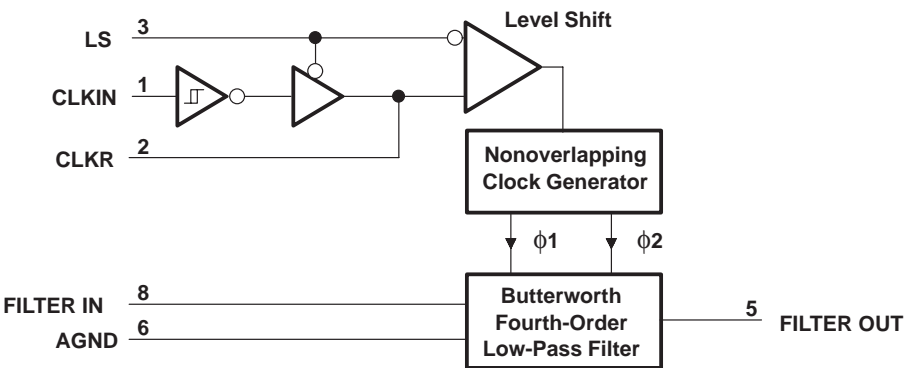
Terminal Functions

TERMINAL NAME	NO.	I/O	DESCRIPTION
AGND	6	I	Analog ground. The noninverting input to the operational amplifiers of the Butterworth fourth-order low-pass filter.
CLKIN	1	I	Clock in. CLKIN is the clock input terminal for CMOS-compatible clock or self-clocking options. For either option, LS is at V_{CC-}. For self-clocking, a resistor is connected between CLKIN and CLKR and a capacitor is connected from CLKIN to ground.
CLKR	2	I	Clock R. CLKR is the clock input for a TTL-compatible clock. For a TTL clock, LS is connected to midsupply and CLKIN can be left open, but it is recommended that it be connected to either V_{CC+} or V_{CC-}.
FILTER IN	8	I	Filter input
FILTER OUT	5	O	Butterworth fourth-order low-pass filter output
LS	3	I	Level shift. LS accommodates the various input clocking options. For CMOS-compatible clocks or self-clocking, LS is at V_{CC-} and for TTL-compatible clocks, LS is at midsupply.
V_{CC+}	7	I	Positive supply voltage terminal
V_{CC-}	4	I	Negative supply voltage terminal

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC\pm}$ (see Note 1) . . . . ± 7 V
Operating free-air temperature range, T_A: TLC04C/MF4A-50C, TLC14C/MF4A-100C . . . . . . 0°C to 70°C
               TLC04I/MF4A-50I, TLC14I/MF4A-100I . . . . −40°C to 85°C
               TLC04M/MF4A-50M, TLC14M/MF4A-100M . . . −55°C to 125°C
Storage temperature range, T_{stg} . . . . −65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds . . . . 260°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and
functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not
implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTE 1: All voltage values are with respect to the AGND terminal.

recommended operating conditions

		TLC04/MF4A-50		TLC14/MF4A-100		UNIT
		MIN	MAX	MIN	MAX	
Positive supply voltage, V_{CC+}		2.25	6	2.25	6	V
Negative supply voltage, V_{CC-}		−2.25	−6	−2.25	−6	V
High-level input voltage, V_{IH}		2		2		V
Low-level input voltage, V_{IL}			0.8		0.8	V
Clock frequency, f_{clock} (see Note 2)	$V_{CC\pm} = \pm 2.5$ V	5	1.5×10^6	5	1.5×10^6	Hz
	$V_{CC\pm} = \pm 5$ V	5	2×10^6	5	2×10^6	
Cutoff frequency, f_{CO} (see Note 3)		0.1	40×10^3	0.05	20×10^3	Hz
Operating free-air temperature, T_A	TLC04C/MF4A-50C, TLC14C/MF4A-100C	0	70	0	70	°C
	TLC04I/MF4A-50I, TLC14I/MF4A-100I	−40	85	−40	85	
	TLC04M/MF4A-50M, TLC14M/MF4A-100M	−55	125	−55	125	

NOTES: 2. Above 250 kHz, the input clock duty cycle should be 50% to allow the operational amplifiers the maximum time to settle while
processing analog samples.
    3. The cutoff frequency is defined as the frequency where the response is 3.01 dB less than the dc gain of the filter.

electrical characteristics over recommended operating free-air temperature range, V_{CC+} = 2.5 V, V_{CC-} = −2.5 V, $f_{clock} \leq$ 250 kHz (unless otherwise noted)

filter section

PARAMETER		TEST CONDITIONS	TLC04/MF4A-50			TLC14/MF4A-100			UNIT
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{OO}	Output offset voltage			25			50		mV
V_{OM}	Peak output voltage	V_{OM+}	$R_L = 10$ kΩ	1.8	2		1.8	2		V
		V_{OM-}		−1.25	−1.7		−1.25	−1.7		
I_{OS}	Short-circuit output current	Source	$T_A = 25$°C, See Note 4		−0.5			−0.5		mA
		Sink			4			4		
I_{CC}	Supply current		$f_{clock} = 250$ kHz		1.2	2.25		1.2	2.25	mA

‡ All typical values are at $T_A = 25$°C.
NOTE 4: $I_{OS(source)}$ is measured by forcing the output to its maximum positive voltage and then shorting the output to the V_{CC-} terminal
     $I_{OS(sink)}$ is measured by forcing the output to its maximum negative voltage and then shorting the output to the V_{CC+} terminal.

electrical characteristics over recommended operating free-air temperature range, V_{CC+} = 5 V, V_{CC-} = −5 V, f_{clock} ≤ 250 kHz (unless otherwise noted)

filter section

PARAMETER		TEST CONDITIONS	TLC04/MF4A-50 MIN	TLC04/MF4A-50 TYP†	TLC04/MF4A-50 MAX	TLC14/MF4A-100 MIN	TLC14/MF4A-100 TYP†	TLC14/MF4A-100 MAX	UNIT
V_{OO}	Output offset voltage			150			200		mV
V_{OM}	Peak output voltage — V_{OM+}	R_L = 10 kΩ	3.75	4.3		3.75	4.5		V
	Peak output voltage — V_{OM-}		−3.75	−4.1		−3.75	−4.1		
I_{OS}	Short-circuit output current — Source	T_A = 25°C, See Note 4		−2			−2		mA
	Short-circuit output current — Sink			5			5		
I_{CC}	Supply current	f_{clock} = 250 kHz		1.8	3		1.8	3	mA
k_{SVS}	Supply voltage sensitivity (see Figures 1 and 2)			−30			−30		dB

† All typical values are at T_A = 25°C.
NOTE 4: $I_{OS(source)}$ is measured by forcing the output to its maximum positive voltage and then shorting the output to the V_{CC-} terminal. $I_{OS(sink)}$ is measured by forcing the output to its maximum negative voltage and then shorting the output to the V_{CC+} terminal.

clocking section

PARAMETER			TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IT+}	Positive-going input threshold voltage	CLKIN	V_{CC+} = 10 V,	V_{CC-} = 0	6.1	7	8.9	V
			V_{CC+} = 5 V,	V_{CC-} = 0	3.1	3.5	4.4	
V_{IT-}	Negative-going input threshold voltage		V_{CC+} = 10 V,	V_{CC-} = 0	1.3	3	3.8	V
			V_{CC+} = 5 V,	V_{CC-} = 0	0.6	1.5	1.9	
V_{hys}	Hysteresis voltage (V_{IT+} − V_{IT-})		V_{CC+} = 10 V,	V_{CC-} = 0	2.3	4	7.6	V
			V_{CC+} = 5 V,	V_{CC-} = 0	1.2	2	3.8	
V_{OH}	High-level output voltage	CLKR	V_{CC} = 10 V	I_O = −10 µA	9			V
			V_{CC} = 5 V		4.5			
V_{OL}	Low-level output voltage		V_{CC} = 10 V	I_O = 10 µA			1	V
			V_{CC} = 5 V				0.5	
	Input leakage current		V_{CC} = 10 V	LS at midsupply, T_A = 25°C			2	µA
			V_{CC} = 5 V				2	
I_O	Output current		V_{CC} = 10 V	CLKR and CLKIN shortened to V_{CC-}	−3	−7		mA
			V_{CC} = 5 V		−0.75	−2		
			V_{CC} = 10 V	CLKR and CLKIN shortened to V_{CC+}	3	7		mA
			V_{CC} = 5 V		0.75	2		

† All typical values are at T_A = 25°C.

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operating characteristics over recommended operating free-air temperature range, V_{CC+} = 2.5 V, V_{CC-} = −2.5 V (unless otherwise noted)

PARAMETER	TEST CONDITIONS		TLC04/MF4A-50			TLC14/MF4A-100			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
Maximum clock frequency, f_{max}	See Note 2		1.5	3		1.5	3		MHz
Clock-to-cutoff-frequency ratio (f_{clock}/f_{co})	$f_{clock} \leq$ 250 kHz, T_A = 25°C		49.27	50.07	50.87	99	100	101	Hz/Hz
Temperature coefficient of clock-to-cutoff frequency ratio	$f_{clock} \leq$ 250 kHz			±25			±25		ppm/°C
Frequency response above and below cutoff frequency (see Note 5)	f_{CO} = 5 kHz, f_{clock} = 250 kHz, T_A = 25°C	f = 6 kHz	−7.9	−7.57	−7.1				dB
		f = 4.5 kHz	−1.7	−1.46	−1.3				
	f_{CO} = 5 kHz, f_{clock} = 250 kHz, T_A = 25°C	f = 3 kHz				−7.9	−7.42	−7.1	dB
		f = 2.25 kHz				−1.7	−1.51	−1.3	
Dynamic range (see Note 6)	T_A = 25°C			80			78		dB
Stop-band frequency attentuation at 2 f_{co}	$f_{clock} \leq$ 250 kHz		24	25		24	25		dB
Voltage amplification, dc	$f_{clock} \leq$ 250 kHz, RS $\leq$ 2 kΩ		−0.15	0	0.15	−0.15	0	0.15	dB
Peak-to-peak clock feedthrough voltage	T_A = 25°C			5			5		mV

† All typical values are at T_A = 25°C.

NOTES: 2. Above 250 kHz, the input clock duty cycle should be 50% to allow the operational amplifiers the maximum time to settle while processing analog samples.
5. The frequency responses at f are referenced to a dc gain of 0 dB.
6. The dynamic range is referenced to 1.06 V rms (1.5 V peak) where the wideband noise over a 30-kHz bandwidth is typically 106 μV rms for the TLC04/MF4A-50 and 135 μV rms for the TLC14/MF4A-100.

operating characteristics over recommended operating free-air temperature range, V_{CC+} = 5 V, V_{CC-} = −5 V (unless otherwise noted)

PARAMETER	TEST CONDITIONS		TLC04/MF4A-50			TLC14/MF4A-100			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
Maximum clock frequency, f_{max}	See Note 2		2	4		2	4		MHz
Clock-to-cutoff-frequency ratio (f_{clock}/f_{co})	$f_{clock} \leq$ 250 kHz, T_A = 25°C		49.58	49.98	50.38	99	100	101	Hz/Hz
Temperature coefficient of clock-to-cutoff frequency ratio	$f_{clock} \leq$ 250 kHz			±15			±15		ppm/°C
Frequency response above and below cutoff frequency (see Note 5)	f_{CO} = 5 kHz, f_{clock} = 250 kHz, T_A = 25°C	f = 6 kHz	−7.9	−7.57	−7.1				dB
		f = 4.5 kHz	−1.7	−1.44	−1.3				
	f_{CO} = 5 kHz, f_{clock} = 250 kHz, T_A = 25°C	f = 3 kHz				−7.9	−7.42	−7.1	dB
		f = 2.25 kHz				−1.7	−1.51	−1.3	
Dynamic range (see Note 6)	T_A = 25°C			86			84		dB
Stop-band frequency attentuation at 2 f_{co}	$f_{clock} \leq$ 250 kHz		24	25		24	25		dB
Voltage amplification, dc	$f_{clock} \leq$ 250 kHz, RS $\leq$ 2 kΩ		−0.15	0	0.15	−0.15	0	0.15	dB
Peak-to-peak clock feedthrough voltage	T_A = 25°C			7			7		mV

† All typical values are at T_A = 25°C.

NOTES: 2. Above 250 kHz, the input clock duty cycle should be 50% to allow the operational amplifiers the maximum time to settle while processing analog samples.
5. The frequency responses at f are referenced to a dc gain of 0 dB.
6. The dynamic range is referenced to 2.82 V rms (4 V peak) where the wideband noise over a 30-kHz bandwidth is typically 142 μV rms for the TLC04/MF4A-50 and 178 μV rms for the TLC14/MF4A-100.

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TYPICAL CHARACTERISTICS

FILTER OUTPUT
vs
SUPPLY VOLTAGE V_{CC+} RIPPLE FREQUENCY

V_{CC+} = 5 V + 50-mV Sine Wave
(0 to 40 kHz)

V_{CC-} = –5 V
Filter in at 0 V
f_{clock} = 250 kHz

Figure 1

FILTER OUTPUT
vs
SUPPLY VOLTAGE V_{CC-} RIPPLE FREQUENCY

V_{CC+} = 5 V
V_{CC-} = –5 V + 50-mV Sine Wave
(0 to 40 kHz)
Filter in at 0 V
f_{clock} = 250 kHz

Figure 2

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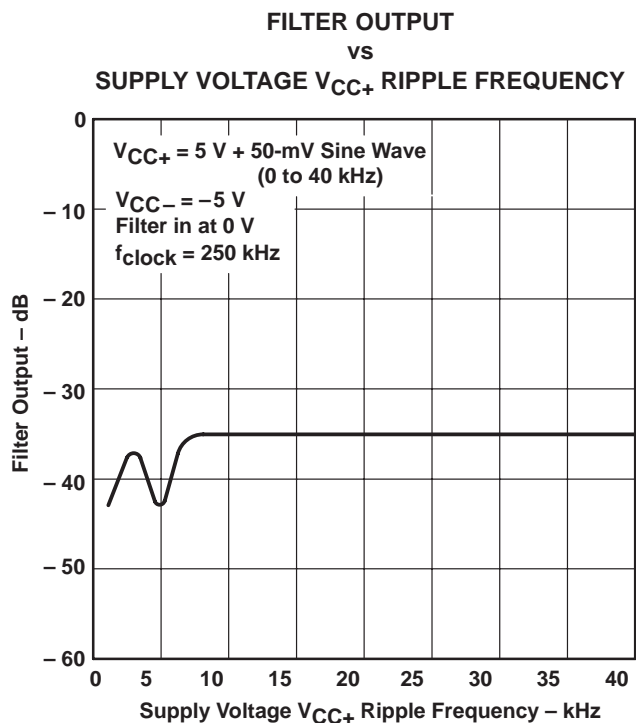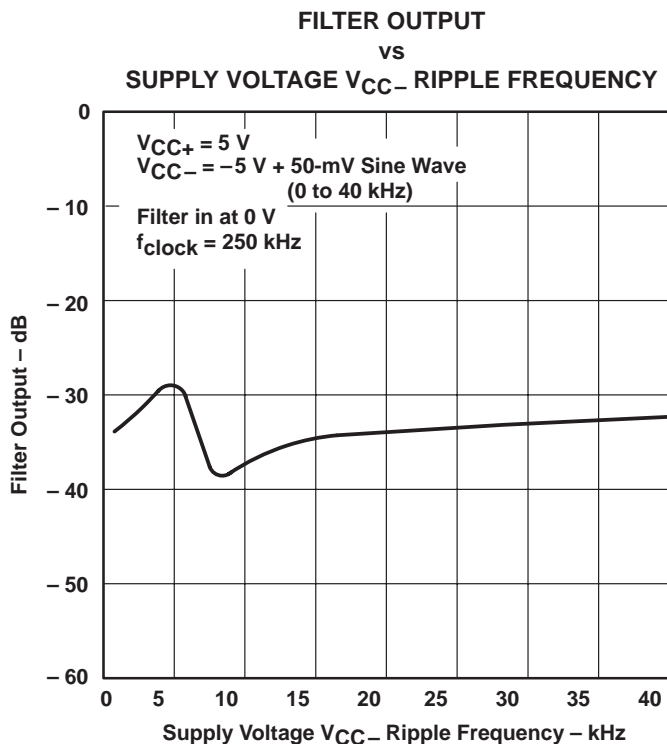
APPLICATION INFORMATION
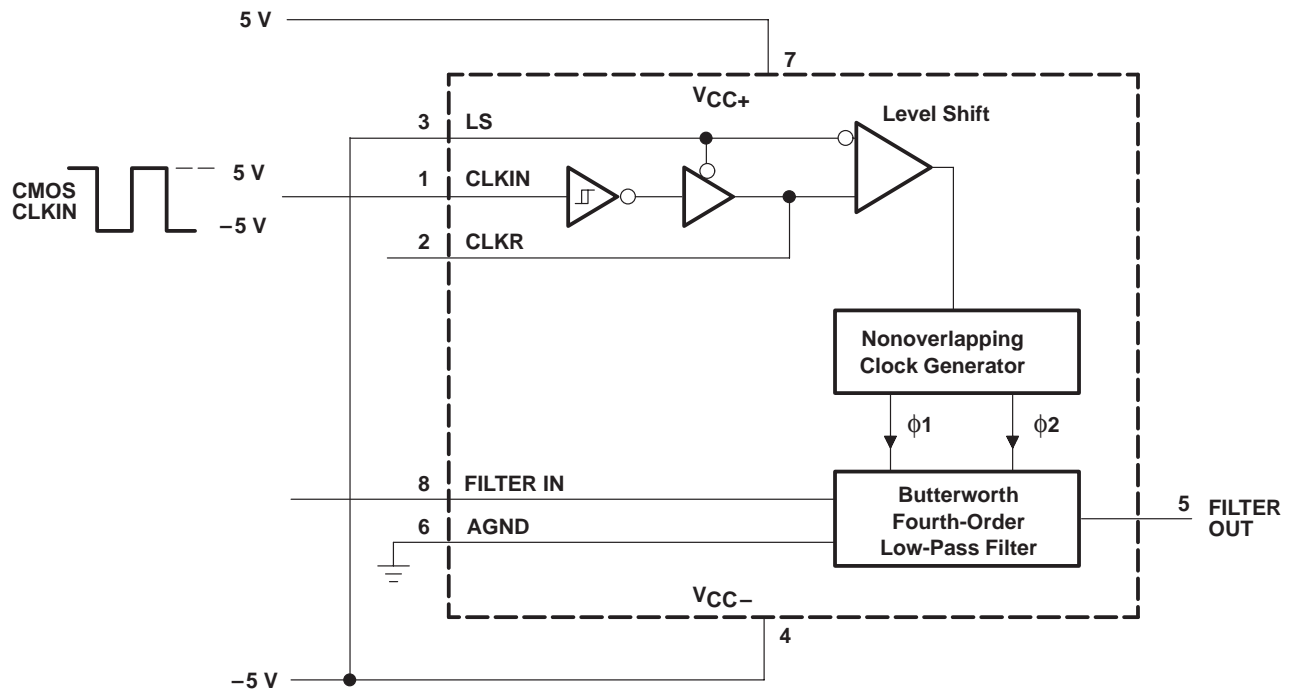
Figure 3. CMOS-Clock-Driven Dual-Supply Operation
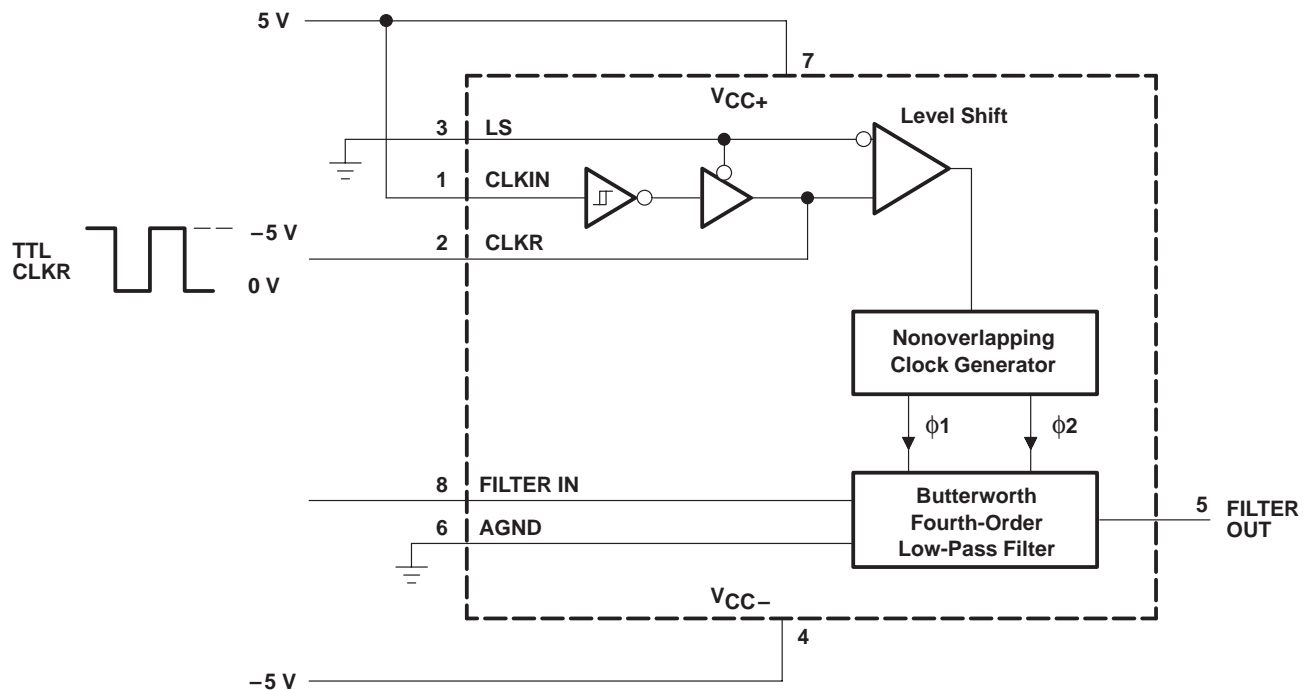
Figure 4. TTL-Clock-Driven Dual-Supply Operation

APPLICATION INFORMATION
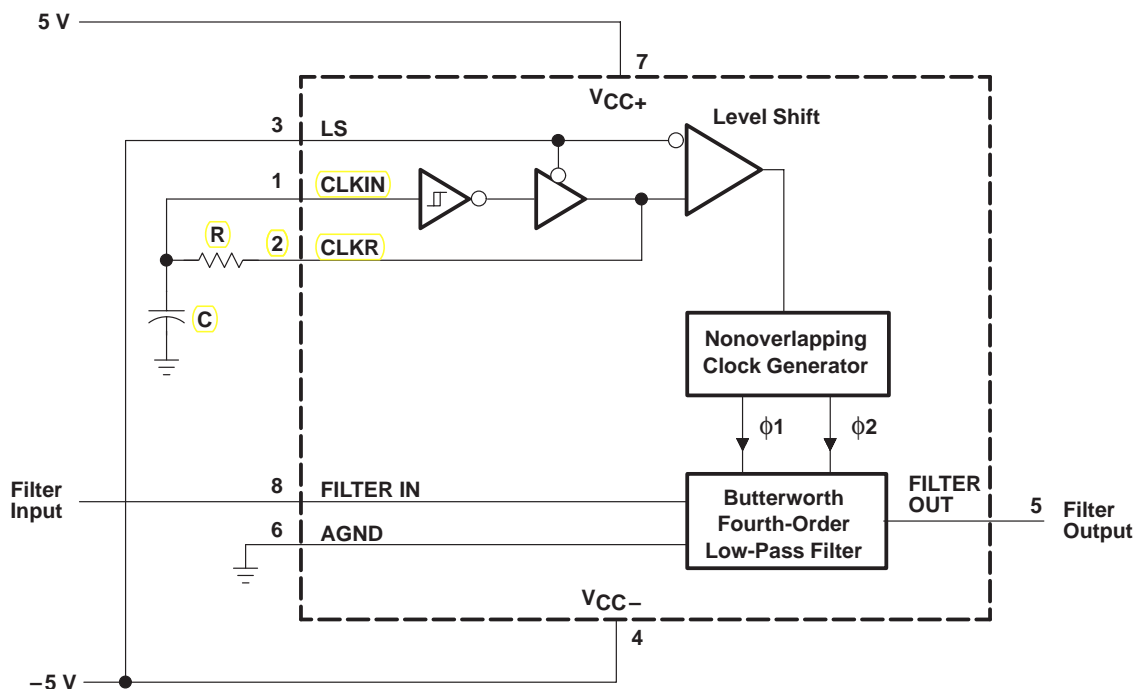
$$f_{clock} = \cfrac{1}{RC \times \ln\left[\left(\cfrac{V_{CC}-V_{IT-}}{V_{CC}-V_{IT+}}\right)\left(\cfrac{V_{IT+}}{V_{IT-}}\right)\right]}$$
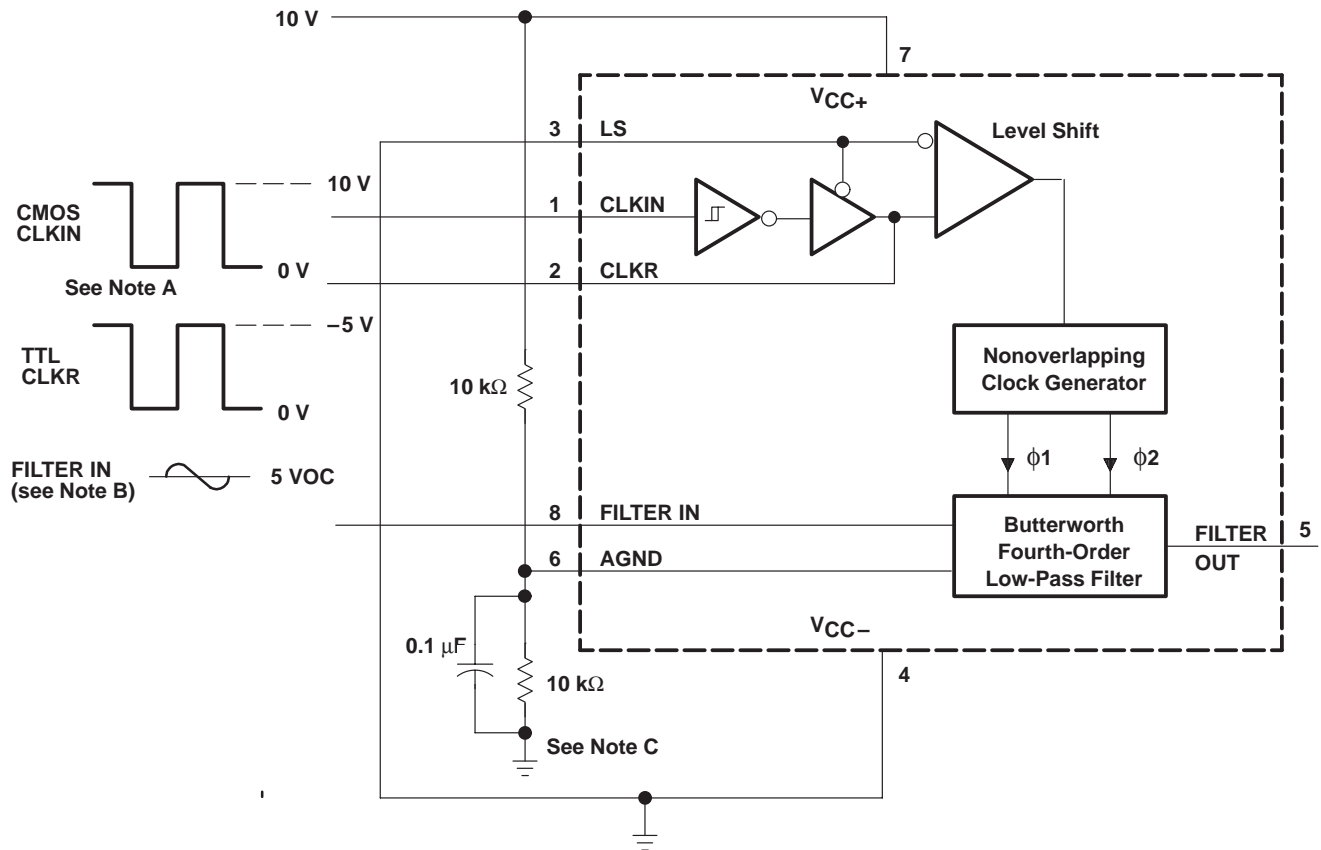
For $V_{CC} = 10$ V

$$f_{clock} = \frac{1}{1.69\ RC}$$

Figure 5. Self-Clocking Through Schmitt-Trigger Oscillator Dual-Supply Operation
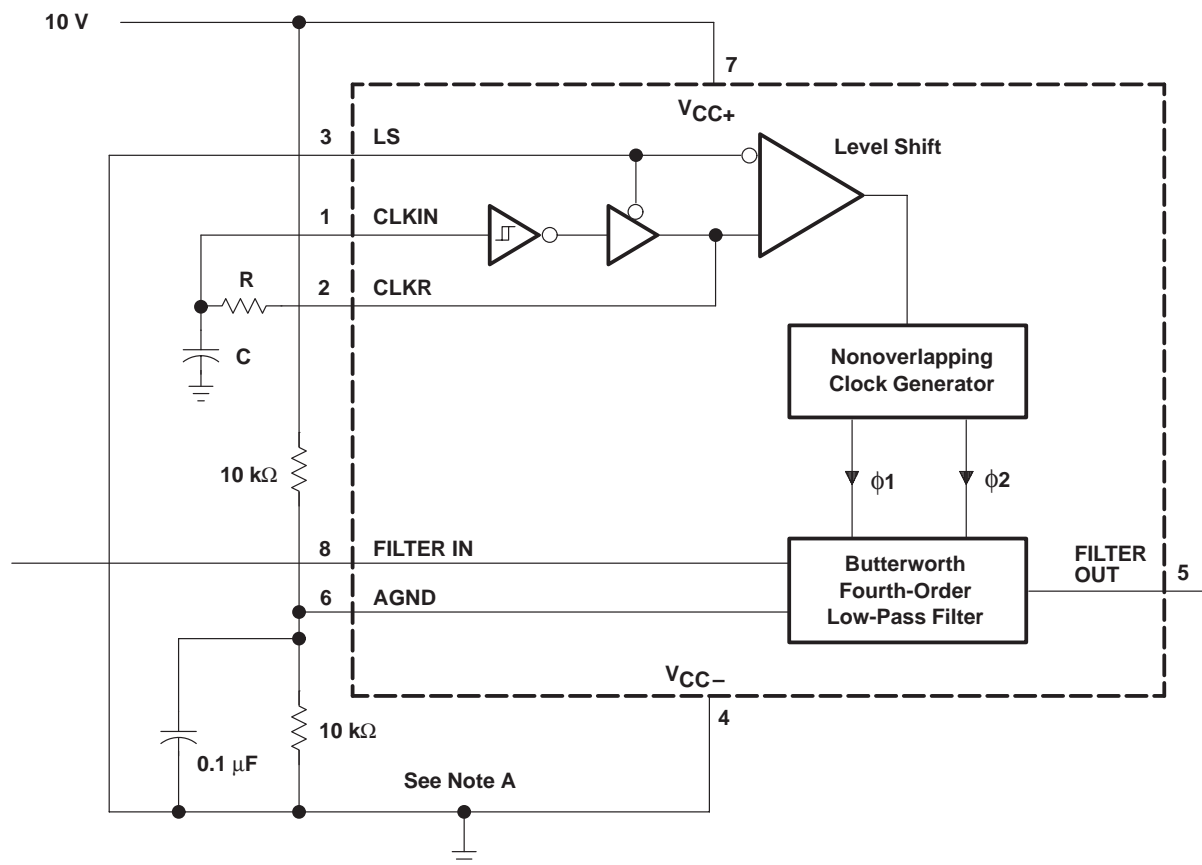
APPLICATION INFORMATION

NOTES: A. The external clock used must be of CMOS level because the clock is input to a CMOS Schmitt trigger.
   B. The filter input signal should be dc-biased to midsupply or ac-coupled to the terminal.
   C. AGND must be biased to midsupply.

Figure 6. External-Clock-Driven Single-Supply Operation

APPLICATION INFORMATION

$$f_{clock} = \frac{1}{RC \times \ln\left[\left(\dfrac{V_{CC} - V_{IT-}}{V_{CC} - V_{IT+}}\right)\left(\dfrac{V_{IT+}}{V_{IT-}}\right)\right]}$$

For V_{CC} = 10 V

$$f_{clock} = \frac{1}{1.69\,RC}$$

NOTE A: AGND must be biased to midsupply.

Figure 7. Self Clocking Through Schmitt-Trigger Oscillator Single-Supply Operation
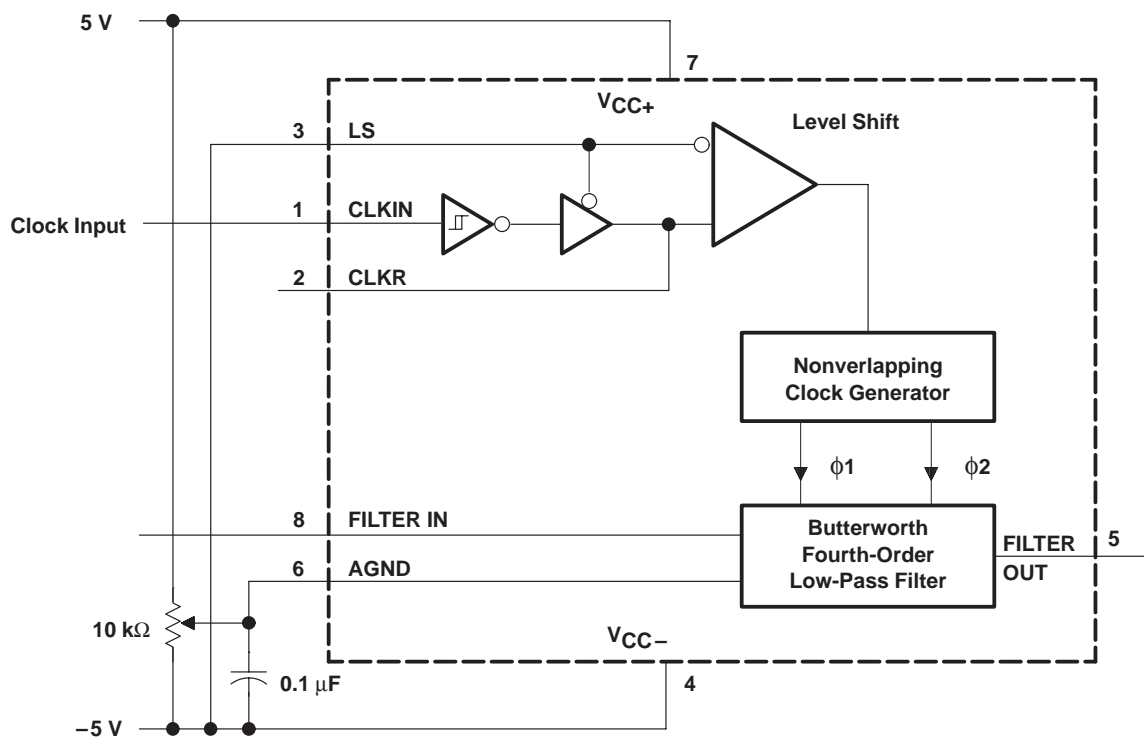
APPLICATION INFORMATION

Figure 8. DC Offset Adjustment

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